

ABSTRACT

In a method and a device for testing a plurality of measured devices in parallel by using a single signal generator and a single bit error measuring device, a serial signal for test is converted into
5 parallel signals corresponding to channels for a plurality of measured devices and a redundant channel to be demultiplexed for the measured devices, a passing signal through the redundant channel is converted into a channel determination signal for specifying an
10 alignment of the measured devices, output signals of the measured devices and the channel determination signal are multiplexed corresponding to a demultiplexing mode, and bit errors are measured from the multiplexed signals and measured devices concerning the bit errors are detected from the channel determination signal.